

WHAT IS CLAIMED IS:

1. A system for detecting asperities on a disc surface, the system comprising:

a glide head, wherein the glide head has an air bearing surface with a peak-to-valley flatness less than about 1 pinch;

an armature for positioning the glide head over the disc; and

a transducer mounted on the glide head, the transducer detecting interactions between the glide head and the disc.

2. The asperity detection system of claim 1 wherein the glide head is cut from a wafer having a wafer surface and the air bearing surface comprises a portion of the wafer surface.

3. The asperity detection system of claim 1 wherein the glide head is cut from a wafer and a side face of the glide head substantially perpendicular to the air bearing surface comprises a cut face.

4. A glide head comprising an air bearing surface having a surface flatness less than about 1 pinch and a transducer that produces a signal in response to contact with the glide head.

5. The glide head of claim 4 wherein said air bearing surface includes rails.

6. The glide head of claim 4 wherein the transducer comprises a PZT transducer mounted on a

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surface opposite the air bearing surface.

7. The glide head of claim 6 wherein the PZT transducer is mounted above the air bearing surface.

8. The glide head of claim 6 wherein the PZT transducer is mounted on a wing.

9. The glide head of claim 4 wherein the transducer comprises a thermal transducer mounted on the air bearing surface.

10. The glide head of claim 4 wherein the air bearing surface has a flatness less than about 0.5 μ inch.

11. A wafer having a surface contoured for the air bearing surfaces of a plurality of glide heads.

12. The wafer of claim 11 wherein the air bearing surface comprise rails.

13. The wafer of claim 11 wherein said contoured surface has a flatness less than about 3 μ m.

14. The wafer of claim 11 wherein the wafer comprises aluminum oxide/titanium carbide.

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Sub 9
Sub 10
B5

Add A²
Add C⁶
Add B⁷